I am pleased to report on the status of IEEE Transactions on Dependable and Secure Computing (TDSC) at end of my second year as editor-in-chief of the journal. TDSC experienced a successful 2015 in terms of quantity and quality of submitted papers. During 2015, a total of 384 new papers were submitted to TDSC; of these 384 papers, 359 are regular papers, 20 are short papers, and 5 are comments papers. In 2014, 2013 and 2012, the number of submitted papers has been 376, 359 and 329, respectively, which shows an upward trend in the number of submissions. To accommodate such growth the editorial board has been expanded in both the number and expertise of reviewers. A specific focus in the recruitment of new editors has been to expand the number of editors in the following areas: networks, hardware security, security usability, biometrics, and security of critical infrastructures. I am very pleased to report that the following new editors joined the editorial board of TDSC in 2015: Dough Blough (US), Lorrie Faith Cranor (US), Srini Devadas (US), Michael Franz (US), Roy Friedman (Israel), Sanjay Kumar Jia (Australia), Zbigniew Kalbarczyk (US), Jun Li (UA), Bruce McMillin (US), Alessandro Piva (Italy), Kui Ren (US), Ting Yu (Qatar).

The editorial board is complemented by two Associate Editors-in-Chief: Dr. Gail-Joon Ahn (US) and Neeraj Suri (Germany). They closely work with the Editor-in-Chief in identifying new editorial board members and topics for special issues and shepherding these special issues. With respect to special issues, two special issues will be published in 2015: Reliable and Secure VANETs, and Cyber Crime. I am pleased to report that three new special issues are currently underway which focus on timely exciting topics in our field: Social Networks Security; Emerging Embedded and Cyber Physical System Security—Challenges and Innovations; Data-Driven Dependability and Security. I hope that you will submit your strongest work to these special issues.

Clearly the success of IEEE TDSC depends firstly on the quality of the submissions. I would like to take this opportunity to thank all the authors who have submitted their work to the journal. I hope that you will continue to submit your best work to IEEE TDSC. I would like also to thank the editors and reviewers for their dedication in ensuring a timely and high quality review process. Last but not least, I would like to thank the IEEE CS staff, and especially our new editorial assistant Leigh Ann Testa, for the continuous support in the journal operations.

Enjoy the forthcoming issues of IEEE TDSC!!

Elisa Bertino
Editor-in-Chief